

Address:



TEST REPORT

Product Name: Wireless anti-loss device

FCC ID: 2BF8U-NTAG

Trademark: N/A

N Tag, AZOK Stamp, airt my, Sualio Tag, F1, F2, F3, F4, F5, F6, F7, F8, F9, F10, Model Number:

F11, F12 F13, F14, F15, F16, F17

Prepared For: Shenzhen Jiatianxia Electronics Co.,Ltd.

301, Block D1, Building D, Yinfeng Industrial Park, Hangcheng Avenue, Sanwei Address:

Community, Hangcheng Street, Baoan District, Shenzhen, China

Manufacturer: Shenzhen Jiatianxia Electronics Co., Ltd.

301, Block D1, Building D, Yinfeng Industrial Park, Hangcheng Avenue, Sanwei

Community, Hangcheng Street, Baoan District, Shenzhen, China

Prepared By: Shenzhen CTB Testing Technology Co., Ltd.

1&2/F., Building A, No.26, Xinhe Road, Xinqiao, Xinqiao Street, Bao'an District, Address:

Shenzhen, Guangdong, China

Sample Received Date: Apr.18, 2024

Sample tested Date: Apr. 18, 2024 to Apr. 26, 2024

Issue Date: Apr. 26, 2024

Report No.: CTB240426011RFX

FCC CFR Title 47 Part 15 Subpart C Section 15.247 Test Standards

ANSI C63.10:2013

Test Results PASS

This is Bluetooth radio test report. Remark:

Compiled by: Reviewed by: Approved by:

Arron 220 Zhou kui

Zhou Kui Arron Liu Bin Mei / Director

Note: If there is any objection to the inspection results in this report, please submit a written report to the company within 15 days from the date of receiving the report. The test report is effective only with both signature and specialized stamp. This result(s) shown in this report refer only to the sample(s) tested. Without written approval of Shenzhen CTB Testing Technology Co., Ltd. this report can't be reproduced except in full. The tested sample(s) and the sample information are provided by the client. "*" indicates the testing items were fulfilled by subcontracted lab. "#" indicates the items are not in CNAS accreditation scope.



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Shenzhen CTB Testing Technology Co., Ltd. Report No.: CTB240426011RFX

11.2	Limit	.31
	Test procedure	
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12.	ANTENNA REQUIREMENT	. 33
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(Note: N/A means not applicable)

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1. VERSION

Report No.	Issue Date	Description	Approved
CTB240426011RFX	Apr. 26, 2024	Original	Valid

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2. TEST SUMMARY

The Product has been tested according to the following specifications:

Test Item	Test Requirement	Test method	Result
AC Power Line Conducted Emission	47 CFR Part 15 Subpart C Section 15.207	ANSI C63.10-2013	N/A
Radiated Spurious emissions	47 CFR Part 15 Subpart C Section 15.205/15.209	ANSI C63.10-2013	PASS
Band edge and RF Conducted Spurious Emissions	47 CFR Part 15 Subpart C Section 15.247(d)/15.205(a)	ANSI C63.10-2013	PASS
Conducted Peak Output Power	47 CFR Part 15 Subpart C Section 15.247 (b)(3)	ANSI C63.10-2013	PASS
Bandwidth	47 CFR Part 15 Subpart C Section 15.247 (a)(2)	ANSI C63.10-2013	PASS
Power Spectral Density	47 CFR Part 15Subpart C Section 15.247 (e)	ANSI C63.10-2013/ KDB 558074 D01v05r02	PASS
Antenna Requirement	47 CFR Part 15 Subpart C Section 15.203/15.247 (b)	\$ 5° 5°	PASS

Remark:

Test according to ANSI C63.10-2013.

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3. MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the Product as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Item	Uncertainty
Occupancy bandwidth	54.3kHz
Conducted output power Above 1G	0.9dB
Conducted output power below 1G	0.9dB
Power Spectral Density , Conduction	0.9dB
Conduction spurious emissions	2.0dB
Out of band emission	2.0dB
3m camber Radiated spurious emission(9K-30MHz)	4.8dB
3m camber Radiated spurious emission(30MHz-1GHz)	4.6dB
3m chamber Radiated spurious emission(1GHz-18GHz)	5.1dB
3m chamber Radiated spurious emission(18GHz-40GHz)	3.4dB
humidity uncertainty	5.5%
Temperature uncertainty	0.63°C
frequency	1×10-7
Conducted Emission (150KHz-30MHz)	3.2 dB
Radiated Emission(30MHz ~ 1000MHz)	4.8 dB
Radiated Emission(1GHz ~6GHz)	4.9 dB

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4. PRODUCT INFORMATION AND TEST SETUP

4.1 Product Information

Model(s): N Tag, AZOK Stamp, airt my, Sualio Tag, F1, F2, F3, F4, F5, F6, F7, F8, F9, F10,

F11, F12 F13, F14, F15, F16, F17

Model Description:

All the model are the same circuit and RF module, only different for model name. T

est sample model: N Tag

Bluetooth Version: Bluetooth 5.2

Hardware Version: V1.0

Software Version: V1.0

Operation Frequency: Bluetooth: 2402-2480MHz

Max. RF output power: Bluetooth: 0.389dBm

Type of Modulation: Bluetooth: GFSK

Antenna installation: Bluetooth: Chip antenna

Antenna Gain: Bluetooth: 1.24dBi
Ratings: DC 3V by battery

4.2 Test Setup Configuration

See test photographs attached in EUT TEST SETUP PHOTOGRAPHS for the actual connections between Product and support equipment.

4.3 Support Equipment

	Item	Equipment	Mfr/Brand	Model/Type No.	Series No.	Note
2007	P. C. D.	CLE CLE CL	CIP CIP CIP C	the city of the ci	in critical	La City

Notes:

- 1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
- 2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

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4.4 Channel List

CH No.	Frequency (MHz)	CH No.	Frequency (MHz)	CH No.	Frequency (MHz)	CH No.	Frequency (MHz)
0	2402	\$ 1	2404	2	2406	3	2408
4	2410	5	2412	6	2414	97	2416
8	2418	9	2420	10	2422	11	2424
12	2426	13	2428	14	2430	15	2432
16	2434	17	2436	18	2438	19	2440
20	2442	21	2444	22	2446	23	2448
24	2450	25	2452	26	2454	27	2456
28	2458	29	2460	30	2462	31	2464
32	2466	33	2468	34	2470	35	2472
36	2474	37	2476	38	2478	39	2480

4.5 Test Mode

All test mode(s) and condition(s) mentioned were considered and evaluated respectively by performing full tests,the worst data were recorded and reported.

Test mode	Low channel	Middle channel	High channel
Transmitting (GFSK)	2402MHz	2440MHz	2480MHz

4.6 Test Environment

Humidity(%):	54
Atmospheric Pressure(kPa):	101 6 6 6 6 6
Normal Voltage(DC):	3.0V
Normal Temperature(°C)	23
Low Temperature(°C)	0
High Temperature(°C)	40

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5. TEST FACILITY AND TEST INSTRUMENT USED

5.1 Test Facility

All measurement facilities used to collect the measurement data are located at 1&2F.,Building A,No. 26,Xinhe Road,Xinqiao,Xinqiao Street,Bao'an District,Shenzhen,Guangdong,China. The site and apparatus are constructed in conformance with the requirements of ANSI C63.4 and CISPR 16-1-1 other equivalent standards.

5.2 Test Instrument Used

No.	Equipment	Manufacturer	Type No.	Serial No.	Firmware Version	Calibrated until
1	Spectrum Analyzer	Agilent	N9020A	MY52090073	A.14.16	2024.07.05
2	Power Sensor	Agilent	U2021XA	MY56120032	40 lo 4	2024.07.05
3	Power Sensor	Agilent	U2021XA	MY56120034		2024.07.05
4	Communication test set	R&S	CMW500	108058	V3.5.80	2024.07.05
5	Spectrum Analyzer	KEYSIGHT	N9020A	MY51289897	A.14.16	2024.07.05
6	Signal Generator	Agilent	N5181A	MY50140365	A.01.60	2024.07.05
7	Vector signal generator	Agilent	N5182A	MY47420195	A.01.87	2024.07.05
8	Communication test set	Agilent	E5515C	MY50102567	B.19.07 (E1962B)	2024.07.06
9	2.4 GHz Filter	Shenxiang	MSF2400-24 83.5MS-1154	20181015001	♦ / I>	2024.07.05
10	5 GHz Filter	Shenxiang	MSF5150-58 50MS-1155	20181015001	& C / C	2024.07.06
11	Filter	Xingbo	XBLBQ-DZA 120	190821-1-1		2024.07.06
12	BT&WI-FI Automatic test software	Micowave	MTS8000	Ver. 2.0.0.0		c" / c"
13	Rohde & Schwarz SFU Broadcast Test System	R&S	SFU	101017	7 57 55	2024.10.30
14	Temperature humidity chamber	Hongjing	TH-80CH	DG-15174	A SP S	2024.07.05
15	234G Automatic test software	Micowave	MTS8200	Ver. 2.0.0.0	0 10 C	1 3
16	966 chamber	C.R.T.	966	0/ 0	070	2024.08.11
17	Receiver	R&S	ESPI	100362	RF_ATTEN_7 (104489/003)	2024.07.05
18	Amplifier	HP	8447E	2945A02747	6 L	2024.07.05
19	Amplifier	Agilent	8449B	3008A01838	SI 5	2024.07.05
20	TRILOG Broadband Antenna	Schwarzbeck	VULB 9168	00869		2024.07.08

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21	Double Ridged Broadband Horn Antenna	Schwarzbeck	BBHA9120D	01911	\$ c50 c55	2024.07.08
22	EMI test software	Fala	EZ-EMC	FA-03A2 RE	P	7
23	Loop Antenna	Schwarzbeck	FMZB 1519B	1519B-224	070	2024.07.08
24	loop antenna	ZHINAN	ZN30900A	GTS534	V N N	/ /
25	40G Horn antenna	A/H/System	SAS-574	588	0,0	2024.10.30
26	Amplifier	AEROFLEX	Aeroflex	097		2024.07.05

	Continuous disturbance								
No.	Equipment	Manufacturer	Model No.	Serial No.	Firmware Version	Calibrated until			
1	LISN	ROHDE&SCHWARZ	ESH3-Z5	100318	15	2024.07.05			
2	Pulse limiter	ROHDE&SCHWARZ	ESH3Z2	357881052	4/4	2024.07.05			
3	EMI TEST RECEIVER	ROHDE&SCHWARZ	ESCI	100428/003	V4.42.SP3	2024.07.05			
4	Coaxial cable	ZDECL	Z302S-NJ-SM AJ-12M	18091905	1.0	2024.07.05			
5	ISN	Schwarzbeck	NTFM8158	183	4 7 A	2024.07.05			
6	Communication test set	Agilent	E5515C	MY50102567	B.19.07 (E1962B)	2024.07.05			
7	Communication test set	R&S	CMW500	108058	V3.5.80	2024.07.05			
8	EZ-EMC	Frad	EMC-con3A1.1	7	7	7 7 00			

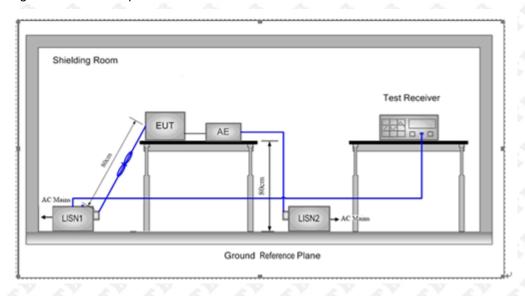
		Radia	ated emission			
No.	Equipment	Manufacturer	Model No.	Serial No.	Firmware Version	Calibrated until
1	Double Ridged Broadband Horn Antenna	Schwarzbeck	BBHA 9120 D	01911	1	2024.07.08
2	TRILOG Broadband Antenna	Schwarzbeck	VULB 9168	00869	\$ 1 \$	2024.07.08
3	Amplifier	Agilent	8449B	3008A01838		2024.07.05
4	Amplifier	HP	8447E	2945A02747		2024.07.05
5	EMI TEST RECEIVER	ROHDE&SCHWARZ	ESCI	100428/003	V4.42.SP3	2024.07.05
6	Coaxial cable	ETS	RFC-SNS-100-N MS-80 NI	7 6		2024.07.05
7	Coaxial cable	ETS	RFC-SNS-100-N MS-20 NI	9 10	1 N	2024.07.05
8	Coaxial cable	ETS	RFC-SNS-100-S MS-20 NI	/ /	010	2024.07.05
9	Coaxial cable	ETS	RFC-NNS-100- NMS-300 NI	67 6		2024.07.05
10	Communication test set	Agilent	E5515C	MY50102567	B.19.07 (E1962B)	2024.07.05
11	Communication test set	R&S	CMW500	108058	V3.5.80	2024.07.05
12	EZ-EMC	Frad	EMC-con3A1.1	07 0		

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6. AC POWER LINE CONDUCTED EMISSION

6.1 Block Diagram Of Test Setup



6.2 Limit

Frequency (MHz)	Conducted limit (dBµV)	
, , ,	Quasi-peak	Average
0.15 - 0.5	66 to 56 ^{Note 1}	56 to 46 ^{Note 1}
0.5 – 5	56	46
5 – 30	60	50

^{*} Decreasing linearly with the logarithm of the frequency

6.3 Test procedure

- 1) The mains terminal disturbance voltage test was conducted in a shielded room.
- 2) The EUT was connected to AC power source through a LISN 1 (Line Impedance Stabilization Network) which provides a $50\Omega/50\mu\text{H} + 5\Omega$ linear impedance. The power cables of all other units of the EUT were connected to a second LISN 2,which was bonded to the ground reference plane in the same way as the LISN 1 for the unit being measured. A multiple socket outlet strip was used to connect multiple power cables to a single LISN provided the rating of the LISN was not exceeded.
- 3) The tabletop EUT was placed upon a non-metallic table 0.8m above the ground reference plane. And for floor-standing arrangement, the EUT was placed on the horizontal ground reference plane,
- 4) The test was performed with a vertical ground reference plane. The rear of the EUT shall be 0.4 m from the vertical ground reference plane. The vertical ground reference plane was bonded to the horizontal ground reference plane. The LISN 1 was placed 0.8 m from the boundary of the unit under

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test and bonded to a ground reference plane for LISNs mounted on top of the ground reference plane. This distance was between the closest points of the LISN 1 and the EUT. All other units of the EUT and associated equipment was at least 0.8 m from the LISN 2.

- 5) In order to find the maximum emission, the relative positions of equipment and all of the interface cables must be changed according to ANSI C63.10:2013 on conducted measurement.
- All modes were tested at AC 120V and 240V, only the worst result of AC 120V 60Hz was reported.
- 7) If a EUT received DC power from the USB Port of Notebook PC,the PC's adapter received AC120V/60Hz power through a Line Impedance Stabilization Network (LISN) which supplied power source and was grounded to the ground plane.

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6.4 Test Result

N/A

NOTE: This EUT is powered by DC power only, this test item is not applicable.

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7. RADIATED SPURIOUS EMISSION

7.1 Block Diagram Of Test Setup

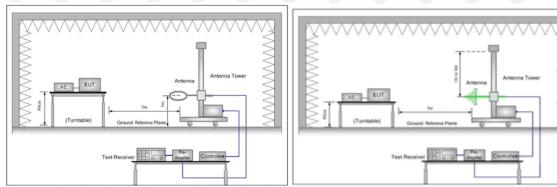
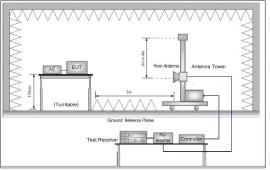


Figure 1. Below 30MHz

Figure 2. 30MHz to 1GHz



7.2 Limit

Spurious Emissions:

Frequency	Field strength (microvolt/meter)	Limit (dBµV/m)	Remark	Measurement distance (m)
0.009MHz-0.490MHz	2400/F(kHz)	() -	(C) C	300
0.490MHz-1.705MHz	24000/F(kHz)	9 , 6	0 -0	30
1.705MHz-30MHz	30	0	' c' c'	30
30MHz-88MHz	100	40.0	Quasi-peak	<> 3⟨>
88MHz-216MHz	150	43.5	Quasi-peak	3
216MHz-960MHz	200	46.0	Quasi-peak	3
960MHz-1GHz	500	54.0	Quasi-peak	3
Above 1GHz	500	54.0	Average	45 3⟨5

Note: 15.35(b),Unless otherwise specified,the limit on peak radio frequency emissions is 20dB above the maximum permitted average emission limit applicable to the equipment under test. This peak limit applies to the total peak emission level radiated by the device.

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7.3 Test procedure

Below 1GHz test procedure as below:

a. The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 3 meter semi-anechoic camber. The table was rotated 360 degrees to determine the position of the highest radiation.

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- b.The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- c.The antenna height is varied from one meter to four meters above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- d.For each suspected emission,the EUT was arranged to its worst case and then the antenna was tuned to heights from 1 meter to 4 meters (for the test frequency of below 30MHz,the antenna was tuned to heights 1 meter) and the rota table table was turned from 0 degrees to 360 degrees to find the maximum reading.
- e.The test-receiver system was set to Peak Detect Function and Specified Bandwidth with Maximum Hold Mode.
- f.If the emission level of the EUT in peak mode was 10dB lower than the limit specified, then testing could be stopped and the peak values of the EUT would be reported. Otherwise the emissions that did not have 10dB margin would be re-tested one by one using peak, quasi-peak or average method as specified and then reported in a data sheet.

Above 1GHz test procedure as below:

- g.Different between above is the test site, change from Semi- Anechoic Chamber to fully Anechoic Chamber and change form table 0.8 meter to 1.5 meter (Above 18GHz the distance is 1 meter and table is 1.5 meter).
- h.Test the EUT in the lowest channel ,the middle channel ,the Highest channel
- i.Repeat above procedures until all frequencies measured was complete.
- j. Full battery is usedduring test

Receiver set:

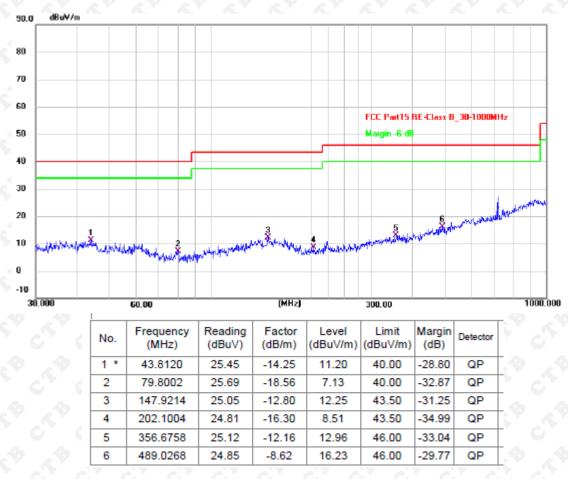
	Frequency	Detector	RBW	VBW	Remark
	0.009MHz-0.090MHz	Peak	10kHz	30KHz	Peak
	0.009MHz-0.090MHz	Average	10kHz	30KHz	Average
	0.090MHz-0.110MHz	Quasi-peak	10kHz	30KHz	Quasi-peak
	0.110MHz-0.490MHz	Peak	10kHz	30KHz	Peak
	0.110MHz-0.490MHz	Average	10kHz	30KHz	Average
	0.490MHz -30MHz	Quasi-peak	10kHz	30kHz	Quasi-peak
	30MHz-1GHz	Quasi-peak	120 kHz	300KHz	Quasi-peak
	Above 4011-	Peak	1MHz	3MHz	Peak
1	Above 1GHz	Peak	1MHz	10Hz	Average

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7.4 Test Result

Below 1GHz Test Results: Antenna polarity: H Worst case-GFSK(low channel)

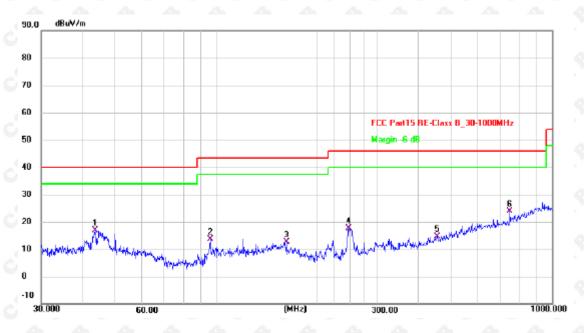


Remark: Factor = Cable lose + Antenna factor - Pre-amplifier; Margin = Measurement - Limit

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Antenna polarity: V Worst case-GFSK(low channel)



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	
1	43.5057	31.03	-14.18	16.85	40.00	-23.15	QP	
2	95.7622	31.43	-17.90	13.53	43.50	-29.97	QP	П
3	161.4740	25.47	-12.82	12.65	43.50	-30.85	QP	Г
4	247.6818	33.20	-15.68	17.52	46.00	-28.48	QP	
5	454.3100	24.45	-9.74	14.71	46.00	-31.29	QP	
6 *	747.4825	26.53	-2.77	23.76	46.00	-22.24	QP	Г

Remark: Factor = Cable lose + Antenna factor - Pre-amplifier; Margin = Measurement – Limit

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Above 1 GHz Test Results:

CH Low (2402MHz) Horizontal:

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Detector
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Type
2402	110.99	-5.84	105.15	N/A	N/A	peak
2402	94.44	-5.84	88.60	N/A	N/A	AVG
4804	58.34	-3.64	54.70	74	-19.30	peak
4804	47.94	-3.64	44.30	54	-9.70	AVG
7206	58.41	-0.95	57.46	74	-16.54	peak
7206	49.86	-0.95	48.91	54	-5.09	AVG

Remark: Factor = Antenna Factor + Cable Loss – Pre-amplifier. Emission level = Reading Result + Factor, Margin = Emission level - Limits

Vertical:

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	O O
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Detector Type
2402	110.21	-5.84	104.37	N/A	N/A	peak
2402	92.34	-5.84	86.50	N/A	N/A	AVG
4804	56.29	-3.64	52.65	74	-21.35	peak
4804	49.17	-3.64	45.53	54	-8.47	AVG
7206	59.64	-0.95	58.69	74	-15.31	peak
7206	48.72	-0.95	47.77	54	-6.23	AVG

Remark: Factor = Antenna Factor + Cable Loss – Pre-amplifier. Emission level = Reading Result + Factor, Margin = Emission level - Limits

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CH Middle (2440MHz) Horizontal:

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Detector
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Type
2440	107.84	-5.71	102.13	N/A	N/A	peak
2440	92.23	-5.71	86.52	N/A	N/A	AVG
4880	55.15	-3.51	51.64	74	-22.36	peak
4880	46.29	-3.51	42.78	54	-11.22	AVG
7320	57.59	-0.82	56.77	74	-17.23	peak
7320	47.58	-0.82	46.76	54	-7.24	AVG

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Margin = Emission level - Limits

Vertical:

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	D-1-0
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Detector Type
2440	107.37	-5.71	101.66	N/A	N/A	peak
2440	91.95	-5.71	86.24	N/A	N/A	AVG
4880	55.37	-3.51	51.86	74	-22.14	peak
4880	45.09	-3.51	41.58	54	-12.42	AVG
7320	56.51	-0.82	55.69	74	-18.31	peak
7320	47.08 r = Antenna Fac	-0.82	46.26	54	-7.74	AVG

Margin = Emission level - Limits

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CH High (2480MHz) Horizontal:

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	69
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Detector Type
2480	107.61	-5.65	101.96	N/A	N/A	peak
2480	92.00	-5.65	86.35	N/A	N/A	AVG
4960	54.40	-3.43	50.97	74	-23.03	peak
4960	46.70	-3.43	43.27	54	-10.73	AVG
7440	57.06	-0.75	56.31	74	-17.69	peak
7440	45.96	-0.75	45.21	54	-8.79	AVG

Vertical:

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	0 0
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Detector Type
2480	106.93	-5.65	101.28	N/A	N/A	peak
2480	92.56	-5.65	86.91	N/A	N/A	AVG
4960	55.84	-3.43	52.41	74	-21.59	peak
4960	45.83	-3.43	42.40	54	-11.60	AVG
7440	55.76	-0.75	55.01	74	-18.99	peak
7440	46.61	-0.75 ctor + Cable L	45.86	54	-8.14	AVG

Remark:

- (1) Measuring frequencies from 9KHz to the 25 GHz, The test range is 9K ~10 times the main wave, and other spurious below the limit of 20dB will not be reflected in the report.
- (2). All modes of GFSK were test at Low, Middle, and High channel, only the worst result of GFSK Low Channel was reported for below 1GHz test.
- (3). For BT above 1GHz test all modes of GFSK were test at Low, Middle, and High channel, only the worst result of GFSK Low Channel was reported.
- (4). By preliminary testing and verifying three axis (X,Y and Z) position of EUT transmitted status, it was found that "Z axis" position was the worst, and test data recorded in this report.
- (5). Radiated emission test from 9kHz to 10th harmonic of fundamental was verified, and no emission found except system noise floor in 9kHz to 30MHz and not recorded in this report.

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Restricted bands around fundamental frequency (Radiated)

Operation Mode: TX CH Low (2402MHz)

Horizontal (Worst case)

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Detector
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Туре
2310	53.96	-5.81	48.15	74	-25.85	peak
2310	0/0	-5.81	0 0 4	54	10	AVG
2390	55.33	-5.84	49.49	74	-24.51	peak
2390	9 19	-5.84		54	(A)	AVG
2400	55.29	-5.84	49.45	74	-24.55	peak
2400		-5.84		54	03/103	AVG

Vertical:

Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Detector
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Туре
2310	54.47	-5.81	48.66	74	-25.34	peak
2310	010	-5.81		54	6 / 6 P	AVG
2390	55.88	-5.84	50.04	74	-23.96	peak
2390	0 /0	-5.84	4 1 4	54		AVG
2400	57.93	-5.84	52.09	74	-21.91	peak
2400		-5.84		54	57/5	AVG

When the peak value is smaller than the AVG limit, AVG is not reflected.

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Operation Mode: TX CH High (2480MHz)

Horizontal (Worst case)

Frequency	Reading Result	Factor	Emission Level	Limits	Margin	Data star Tura
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Detector Type
2483.50	55.62	-5.65	49.97	74	-24.03	peak
2483.50		-5.65		54		AVG
2500.00	53.36	-5.65	47.71	74	-26.29	peak
2500.00	67167	-5.65	C 1 C 5	54	616	AVG

Remark: Factor = Antenna Factor + Cable Loss – Pre-amplifier. Emission level = Reading Result + Factor, Margin = Emission level - Limits

Vertical:

Frequency	Reading Result	Factor	Emission Level	Limits	Margin	Detector Type
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	Detector Type
2483.50	55.31	-5.65	49.66	74	-24.34	peak
2483.50	P	-5.65	7 3	54	P	AVG
2500.00	53.85	-5.65	48.20	74	-25.80	peak
2500.00	67/65	-5.65	67/67	54	Si o	AVG

Remark: Factor = Antenna Factor + Cable Loss – Pre-amplifier. Emission level = Reading Result + Factor, Margin = Emission level - Limits

Remark: All the other emissions not reported were too low to read and deemed to comply with FCC limit.

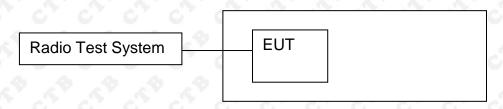
When the peak value is smaller than the AVG limit, AVG is not reflected.

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8. BAND EDGE AND RF COUNDUCTED SPURIOUS EMISSIONS

8.1 Block Diagram Of Test Setup



8.2 Limit

In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20 dB. Attenuation below the general limits specified in §15.209(a) is not required. In addition, radiated emissions which fall in the restricted bands, as defined in §15.205(a), must also comply with the radiated emission limits specified in §15.209(a) (see §15.205(c)).

8.3 Test procedure

- 1. Remove the antenna from the EUT and then connect a low RF cable from the antenna port to the spectrum;
- 2. Set the spectrum analyzer:

Blow 30MHz:

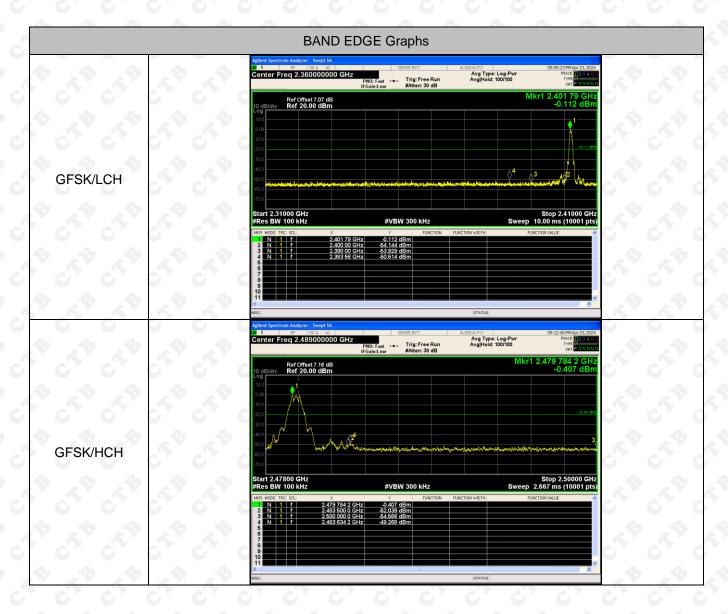
RBW = 100kHz,VBW = 300kHz,Sweep = auto Detector function = peak,Trace = max hold Above 30MHz: RBW = 100KHz,VBW = 300KHz,Sweep = auto

Detector function = peak,Trace = max hold

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8.4 Test Result





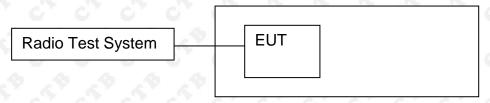


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9. COUDUCTED OUTPUT POWER

9.1 Block Diagram Of Test Setup



9.2 Limit

	FCC	Part15 (15.247) ,Subp	oart C	
Section	Test Item	Limit	Frequency Range (MHz)	Result
15.247(b)(3)	Output Power	1 watt or 30dBm	2400-2483.5	PASS

9.3 Test procedure

- 1. Remove the antenna from the EUT and then connect a low RF cable from the antenna port to the spectrum.
- 2. Set the spectrum analyzer: RBW = 2MHz. VBW = 6MHz. Channel power measurement. Sweep = auto; Detector Function = peak.
- 3. Keep the EUT in transmitting at lowest, middle and highest channel individually. Record the max value.

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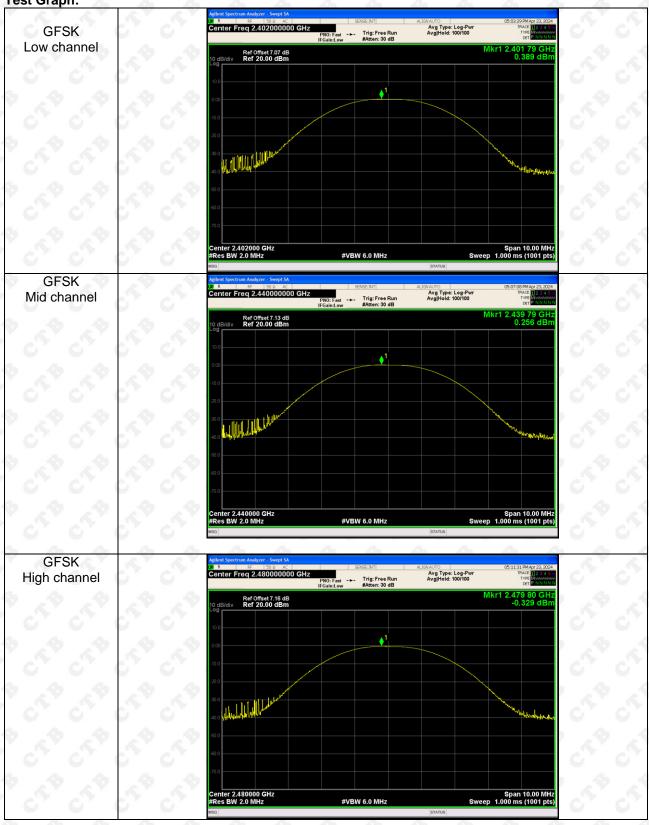
9.4 Test Result

Mode	Channel.	Maximum Output Power [dBm]	Limit[dBm]	Verdict
0,0	LCH	0.389	30	PASS
GFSK	MCH	0.256	30	PASS
	HCH	-0.329	30	PASS

Mode	Channel.	Duty Cycle(%)	Correction Factor (dB)
Ch. Ch.	LCH	100	0 0
GFSK	мсн	100	A A A O O A
	нсн	100	0

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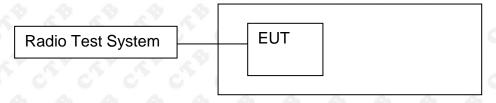
Test Graph:





10. 6DB OCCUPIED BANDWIDTH

10.1 Block Diagram Of Test Setup



10.2 Limit

FCC Part15 (15.247) ,Subpart C					
Section	Test Item	Limit	Frequency Range (MHz)	Result	
15.247(a)(2)	Bandwidth	>= 500KHz (6dB bandwidth)	2400-2483.5	PASS	

10.3 Test procedure

- 1. Rem1. Set RBW = 100 kHz.
- 2. Set the video bandwidth (VBW) \geq 3 x RBW.
- 3. Detector = Peak.
- 4. Trace mode = max hold.
- 5. Sweep = auto couple.
- 6. Allow the trace to stabilize.
- 7. Measure the maximum width of the emission that is constrained by the frequencies associated with the two outermost amplitude points (upper and lower frequencies) that are attenuated by 6 dB relative to the maximum level measured in the fundamental emission.

10.4 Test Result

Test Mode	Frequency	6dB Bandwidth (MHz)	Limit (KHz)	Result
GFSK	Low channel	0.65	>= 500	PASS
	Mid channel	0.646	>= 500	PASS
	High channel	0.651	>= 500	PASS

Note: All modes of operation were Pre-scan and the worst-case emissions are reported.

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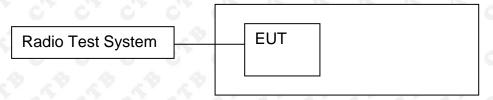
Test Graph:





11. POWER SPECTRAL DENSITY

11.1 Block Diagram Of Test Setup



11.2 Limit

	FCC Part15 (15	.247) ,Subpart C		
Section	Test Item	Limit	Frequency Range (MHz)	Result
15.247	Power Spectral Density	8 dBm (in any 3KHz)	2400-2483.5	PASS

11.3 Test procedure

- 1. Set analyzer center frequency to DTS channel center frequency.
- 2. Set the span to 1.5 times the DTS bandwidth.
- 3. Set the RBW to: $3 \text{ kHz} \leq \text{RBW} \leq 100 \text{ kHz}$.
- 4. Set the VBW \geq 3 x RBW.
- 5. Detector = peak.
- 6. Sweep time = auto couple.
- 7. Trace mode = max hold.
- 8. Allow trace to fully stabilize.
- 9. Use the peak marker function to determine the maximum amplitude level within the RBW.
- 10. If measured value exceeds limit, reduce RBW (no less than 3 kHz) and repeat.

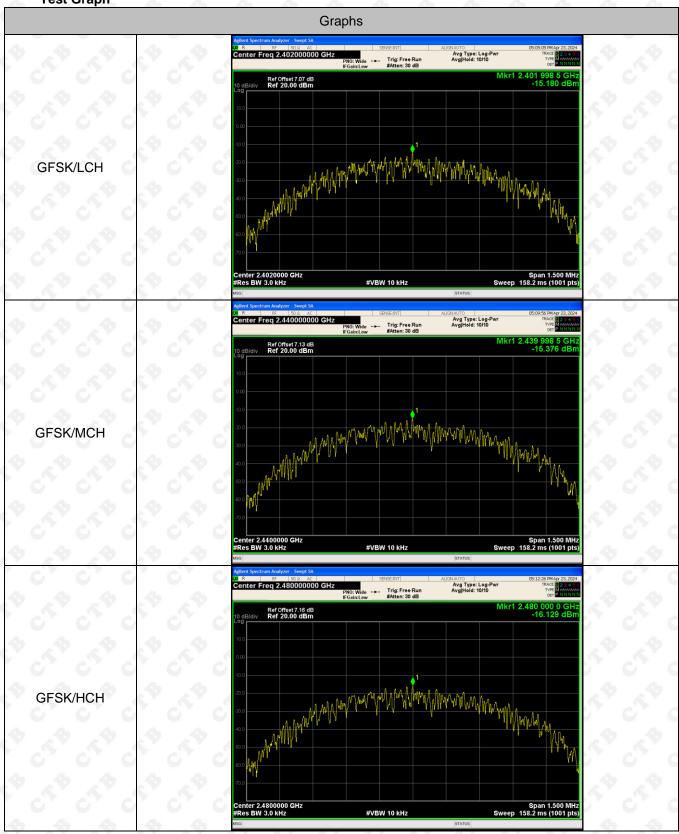
11.4 Test Result

Mode	Channel.	Power Spectral Density (dBm/3KHz)	Limit(dBm/3KHz)	Verdict
GFSK	LCH	-15.18	8	PASS
GFSK	МСН	-15.376	8	PASS
GFSK	НСН	-16.129	8	PASS

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Test Graph



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12. ANTENNA REQUIREMENT

15.203 requirement:

An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator, the manufacturer may design the unit so that a broken antenna can be replaced by the user, but the use of a standard antenna jack or electrical connector is prohibited.

15.247(b) (4) requirement:

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The conducted output power limit specified in paragraph (b) of this section is based on the use of antennas with directional gains that do not exceed 6 dBi. Except as shown in paragraph (c) of this section, if transmitting antennas of directional gain greater than 6 dBi are used, the conducted output power from the intentional radiator shall be reduced below the stated values in paragraphs (b)(1),(b)(2), and (b)(3) of this section, as appropriate, by the amount in dB that the directional gain of the antenna exceeds 6 dBi.

EUT Antenna:

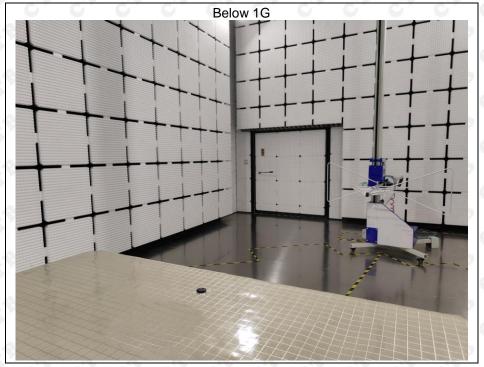
The EUT antenna is Chip antenna. The best case gain of the antenna is 1.24dBi.

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13. EUT TEST SETUP PHOTOGRAPHS

Radiated Emissions





**** END OF REPORT ****

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